

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Babich et al.

: Date: November 10, 2003

Serial Number: N/A

: Group Art Unit: N/A

Filed: Herewith

: Examiner: Unknown

Title: Etch Selectivity Enhancement for
Tunable Etch Resistant Anti-Reflective
Layer

: IBM CORPORATION
Intellectual Property Law
: Dept. 18G/Bldg. 300-482
2070 Route 52
Hopewell Junction, New York 12533-6531

INFORMATION DISCLOSURE STATEMENT (IDS) UNDER 37 CFR 1.97

Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

The attached Form PTO-1449, and any attached foreign patent office search report, provides a listing of information which may be relevant to the subject application. This IDS is not intended as a representation that better art is not available, nor that the information provided is prior art.

This IDS is submitted under:

 X 37 CFR 1.97(b) - No Fee.

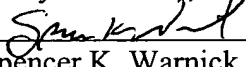
 37 CFR 1.97(c) - No Fee. Each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application. This communication is dated _____, which is not more than 3 months prior to the mailing of this statement.

 37 CFR 1.97(c) - Fee.

 37 CFR 1.97(d) - Fee, Certification & Petition.

The Commissioner is authorized to charge payments of any associated fees required under 37 CFR 1.17(p) and (i) (1) to Deposit Account No. 09-0458 (IBM).

Respectfully submitted,

By: 
Spencer K. Warnick
Registration No. 40,398
Telephone No.: (518) 449-0044

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

FIS920030270US1

Application Number

Applicant(s)

Babich et al.

Filing Date

Herewith

Group Art Unit

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		US 6,514,667 B2	02/2003	Angelopoulos et al.			
		US 6,316,167 B1	11/2001	Angelopoulos et al.			
		US 6,147,009	11/2000	Grill et al.			
		US 6,074,951	06/2000	Kleinhenz et al.			
		5,876,879	03/1999	Kleinhenz et al.			
		5,838,055	11/1998	Kleinhenz et al.			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.